

Notice of References Cited

Application/Control No.

10/529,682

Applicant(s)/Patent Under
Reexamination
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Examiner

JAYESH A. PATEL

Art Unit

2624

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,921,200	07-2005	Booyesen et al.	378/205
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	Ion Imaging System software Whip, Imaging manual whip Basic steps, Pages 1-4
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.